

Partial translation of JP Laid-open 2003-109222

[0052]

Further, depending upon the type of the optical disk, an environmental condition such as a small change in operating temperature, or the like, it is possible to omit processing for the integrated-learning trial writing in step 63 shown in FIG. 1.

Partial translation of Drawings

FIG. 1

52	Collect management information
53	Read nonvolatile memory contents
54	Does manufacturer information match?
55	Pw/Pe scanning
56	Pe scanning
57	Pw scanning
58	Shift trial writing
59	Does manufactured item-number/time information match?
60	Simple Pe scanning
61	Simple Pw scanning
62	Does serial number information match?
63	Integrated-learning trial writing
64	Store into volatile memory
66	Will media be ejected?

68 Has already been recorded into nonvolatile
memory?

69 Store into nonvolatile memory